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TABLE OF CONTENTS

LOW-FREQUENCY NOISE IN SEMICONDUCTOR DEVICES - STATE-OF-THE-ART AND FUTURE PERSPECTIVES PLENARY PAPER.....	1
<i>M. Jamal Deen</i>	
GETTING INFORMATION FROM THE MIXED ELECTRICAL-HEAT NOISE	5
<i>Adeline Crépieux ; Paul Eyméoud ; Fabienne Michelin</i>	
FACTS AND MYTHS ABOUT ZERO-POINT THERMAL NOISE, AND INFORMATION ENTROPY VERSUS THERMAL ENTROPY	9
<i>L. B. Kish ; G. A. Niklasson ; C. G. Granqvist ; D. K. Ferry ; J. M. Smulko</i>	
PHYSICAL 1/F NOISE AND PHASE NOISE IN PIEZOELECTRICS, MEMS RESONATORS AND SENSORS.....	11
<i>P. H. Handel</i>	
MEASURING ELECTRON ENERGY DISTRIBUTION BY CURRENT FLUCTUATIONS.....	15
<i>S. U. Piatrusha ; V. S. Khrapai</i>	
NOISE CHARACTERIZATION OF MOLECULAR JUNCTIONS.....	19
<i>V. Handziuk ; M. Coppola ; V. Sydoruk ; F. Gasparyan ; D. Mayer ; S. Vitusevich</i>	
FLICKER NOISE IN GRAPHENE-BASED HALL SENSORS	23
<i>A. Porciatti ; Z. Wang ; P. Marconcini ; G. Pennelli ; G. Basso ; D. Neumaier ; M. Macucci</i>	
SYMMETRIZED AND NON-SYMMETRIZED NOISE FROM WEAK MEASUREMENTS IN MESOSCOPIC CIRCUITS.....	27
<i>Wolfgang Belzig ; Johannes Bülte ; Adam Bednorz ; Christoph Bruder</i>	
STOCHASTIC DYNAMICS OF GENE EXPRESSION IN DEVELOPING FLY EMBRYOS.....	30
<i>David M. Holloway ; Alexander V. Spirov</i>	
A NOVEL FLUCTUATIONAL APPROACH TO ANALYSIS OF THE PERMEATION IN ION CHANNELS.....	34
<i>Igor A Khovanov ; Salvatore M Cosseddu</i>	
KINETIC MODEL OF SELECTIVITY AND CONDUCTIVITY OF THE KCSA FILTER.....	38
<i>W. A. T. Gibby ; D. G. Luchinsky ; I. Kh. Kaufman ; A. Ward ; P. V. E. McClintock</i>	
SPECTRAL ANALYSIS METHOD FOR SLEEP-STATE CYCLE BASED ON THE CORTICO-THALAMO-CORTICAL LOOP STRENGTH ESTIMATION.....	42
<i>Ikuhiro Yamaguchi ; Akifumi Kishi ; Fumiharu Togo ; Toru Nakamura ; Yoshiharu Yamamoto</i>	
VACUUM-NOISE-INDUCED MULTIMODE CORRELATIONS IN A SUPERCONDUCTING CAVITY	46
<i>Pasi Lähteenmäki ; Gheorghe Sorin Paraoanu ; Pertti J. Hakonen</i>	
A MODIFIED RANDOM TELEGRAPH SIGNAL WITH A 1/F PSD	48
<i>R. M. Howard</i>	
MICROSCOPIC MODELING OF FLUCTUATIONS IN POLAR SEMICONDUCTORS WITH HIGH DENSITY ELECTRON GAS	52
<i>Mindaugas Ramonas</i>	
ANALYSIS OF TRAP-INDUCED NOISE IN ORGANIC LIGHT-EMITTING DIODES BASED ON THE MASTER EQUATION	56
<i>Weifeng Zhou ; Christoph Zimmermann ; Christoph Jungemann</i>	
MONTE CARLO CALCULATION OF $IN_{0.53}GA_{0.47}AS$ AND INAS NOISE PARAMETERS	60
<i>Slyman Karishy ; Christophe Palermo ; Giulio Sabatini ; Hugues Marinchio ; Luca Varani ; Javier Mateos ; Tomás González</i>	
STATISTICAL COMPACT MODELING OF LOW FREQUENCY NOISE IN BURIED-CHANNEL, NATIVE, AND STANDARD MOSFETS	64
<i>Nikolaos Mavredakis ; Matthias Bucher ; Predrag Habas ; Alexandre Acovic ; René Meyer</i>	
INFLUENCE OF EXTERNAL POTENTIALS ON HETEROGENEOUS DIFFUSION PROCESSES	68
<i>Rytis Kazakevicius ; Julius Ruseckas</i>	
NOISE PARAMETERS OF SIGE HBTS IN MMW RANGE: TOWARDS A FULL IN SITU MEASUREMENT EXTRACTION.....	72
<i>F. Danneville ; M. Deng ; S. Bouvot ; J. Azevedo Goncalves ; S. Lépilliet ; G. Ducournau ; C. Gaquière ; G. Dambrine ; A. Bossuet ; T. Quémerais ; G. E. Lauga-Larroze ; J-M Fournier ; P. Chevalier ; D. Gloria</i>	
NOISE FIGURE VERIFICATION OF Y-FACTOR AND COLD SOURCE METHODS.....	76
<i>Joel Dunsmore ; Keysight Fellow</i>	
A NEW APPROACH TO DC REMOVAL IN HIGH GAIN, LOW NOISE VOLTAGE AMPLIFIERS	80
<i>G. Scandurra ; G. Cannatà ; G. Giusi ; C. Ciofi</i>	

A DIFFERENTIAL-INPUT, DIFFERENTIAL-OUTPUT PREAMPLIFIER TOPOLOGY FOR THE DESIGN OF ULTRA-LOW NOISE VOLTAGE AMPLIFIERS	84
<i>G. Scandurra ; G. Cannatà ; G. Giusi ; C. Ciofi</i>	
PORTABLE MEASUREMENT SYSTEM FOR BREATH ANALYSIS BY REAL-TIME FLUCTUATION ENHANCED SENSING METHOD	88
<i>M. Trawka ; J. Smulko ; T. Chludzinski</i>	
LOW FREQUENCY NOISE IN 2D MATERIALS: GRAPHENE AND MOS₂	91
<i>S. L. Rumyantsev ; M. S. Shur ; G. Liu ; A. A. Balandin</i>	
SHOT NOISE IN THE EDGE STATES OF 2D TOPOLOGICAL INSULATORS.....	95
<i>Kirill Nagaev ; Pavel Aseev</i>	
THEORY AND APPLICATIONS OF DETRENDING-OPERATION-BASED FRACTAL-SCALING ANALYSIS	99
<i>Ken Kiyono</i>	
WEAK SIGNAL DETECTION FROM NOISY SIGNAL USING STOCHASTIC RESONANCE WITH PARTICLE SWARM OPTIMIZATION TECHNIQUE	103
<i>Sumit Kumar ; Rajib Kumar Jha</i>	
VARIABILITY OF LOW FREQUENCY NOISE AND MISMATCH IN CORNER DOPED AND STANDARD CMOS TECHNOLOGY	107
<i>Mathieu Coustans ; Farzan Jazaeri ; Christian Enz ; François Krummenacher ; Maher Kayal ; René Meyer ; Alexandre Acovic ; Predrag Habaš ; Jérôme Lolivier ; Matthias Bucher</i>	
LINEAR ANALYSIS OF PHASE NOISE IN LC OSCILLATORS IN DEEP SUBMICRON CMOS TECHNOLOGIES.....	111
<i>Francesco Chicco ; Raffaele Capoccia ; Alessandro Pezzotta ; Christian Enz</i>	
MODELING OF LF FLUCTUATIONS INDUCED TO THE POWER GRID WITH RENEWABLE GENERATION	115
<i>Alexios Birbas ; Efthymios Housos ; Nikos Tzanis ; Alex Papalexopoulos</i>	
A FULLY BALANCED ULTRA-WIDE BAND MIXER MMIC WITH MULTI-TANH TRIPLET INPUT FOR HIGH DYNAMIC RANGE RADAR RECEIVER SYSTEMS	119
<i>Mantas Sakalas ; Niko Joram ; Frank Ellinger</i>	
NOISE AND GAIN OF AN ERBIUM-DOPED FIBER AMPLIFIER FOR DELAY-LINE OPTOELECTRONIC OSCILLATOR.....	123
<i>K. Mikitchuk ; A. Chizh ; S. Malyshev</i>	
TIME DEPENDENT LINEWIDTH: BEAT-NOTE DIGITAL ACQUISITION AND NUMERICAL ANALYSIS	127
<i>Nicolas Von Bandel ; Mikhael Myara ; Baptiste Chomet ; Mohamed Sellahi ; Tahar Souici ; Remi Dardaillon ; Philippe Signoret</i>	
LOCALIZATION OF DARK CURRENT RANDOM TELEGRAPH SIGNAL SOURCES IN PINNED PHOTODIODE CMOS IMAGE SENSORS	131
<i>Clémentine Durnez ; Vincent Goiffon ; Serena Rizzolo ; Pierre Magnan ; Cédric Virmontois ; Laurent Rubaldo</i>	
TERAFET DETECTOR FOR MEASURING POWER FLUCTUATIONS OF 4.75-THZ QCL-GENERATED RADIATION	135
<i>Justinas Zdanevicius ; Kestutis Ikamas ; Jonas Matukas ; Alvydas Lisauskas ; Heiko Richter ; Heinz-Wilhelm Hübers ; Maris Bauer ; Hartmut G. Roskos</i>	
EFFICIENT DETECTION OF SHORT-PULSE THZ RADIATION WITH FIELD EFFECT TRANSISTORS	139
<i>Kestutis Ikamas ; Alvydas Lisauskas ; Maris Bauer ; Adam Rämer ; Sylvain Massabeau ; Dovile Cibiraite ; Marek Burakevic ; Serguei Chevtchenko ; Juliette Mangeney ; Wolfgang Heinrich ; Viktor Krozery ; Hartmut G. Roskosy</i>	
EXPERIMENTAL INVESTIGATION OF STOCHASTIC RESONANCE IN A 65NM CMOS ARTIFICIAL NEURON	143
<i>Sara Hedayat ; Ilias Sourikopoulos ; Christophe Loyez ; Francois Danneville ; Laurent Clavier ; Virginie Hoel ; Alain Cappy</i>	
IMPROVING THE LOW-FREQUENCY NOISE PERFORMANCE OF INPUT/OUTPUT DRAM PERIPHERAL PMOSFETS.....	147
<i>E. Simoen ; B. J. O'Sullivan ; R. Ritzenthaler ; E. Dentoni Litta ; T. Schram ; N. Horiguchi ; V. Machkaoutsan ; P. Fazan ; Y. Li</i>	
IMPACT OF CHANNEL ORIENTATION ON LOW FREQUENCY NOISE PERFORMANCES OF UTBOX NMOSFETS OPERATED AT LIQUID NITROGEN TEMPERATURE	151
<i>B. Nafaa ; B. Cretu ; N. Ismail ; O. Touayar ; E. Simoen</i>	
1/F NOISE AND INTERMITTENCY DUE TO ELECTRON-PHONON SCATTERING IN SEMICONDUCTOR MATERIALS	155
<i>Ferdinand Grüneis</i>	

LOW FREQUENCY NOISE SPECTROSCOPY OF MULTI-WALLED CARBON NANOTUBES COMPOSITES.....	159
<i>S. Pralgauskaite ; J. Matukas ; M. Tretjak ; J. Macutkevicius ; J. Banys ; P. Kuzhir ; E. Ivanov ; R. Kotsilkova</i>	
TWO LEVEL TELEGRAPHIC CONDUCTIVITY FLUCTUATIONS IN FERROMAGNETIC INSULATING MANGANITE SINGLE CRYSTALS	163
<i>Jacek Przybytek ; Jan Fink-Finowicki ; Grzegorz Jung</i>	
FLUCTUATION SCALING IN METALS.....	167
<i>Sofie Beyne ; Tim Beyne</i>	
HIGH FREQUENCY AND NOISE PERFORMANCE OF GFETS.....	171
<i>W. Wei ; D. Fadil ; E. Pallecchi ; G. Dambrine ; H. Happy ; M. Deng ; S. Fregonese ; T. Zimmer</i>	
EFFICIENT VIBRATION ENERGY HARVESTING THROUGH NOISE INDUCED TRANSITIONS.....	176
<i>Michele Bonnin ; Fabio L. Traversa ; Fabrizio Bonani</i>	
COMPREHENSIVE NOISE ANALYSIS IN PPG READ-OUT CHAINS.....	180
<i>Antonino Caizzzone ; Assim Boukhayma ; Christian Enz</i>	
NOISE AND UNCERTAINTY IN COMPARATOR/TDC SENSOR READOUT CIRCUITS.....	184
<i>C. Spathis ; A. Birbas ; K. Georgakopoulou ; M. Birbas</i>	
RELATION BETWEEN SELECTIVITY AND CONDUCTIVITY IN NARROW ION CHANNELS.....	188
<i>D. G. Luchinsky ; W. A. T. Gibby ; I. Kh. Kaufman ; P. V. E. McClintock ; D. A. Timucin</i>	
EFFECT OF LOCAL BINDING ON STOCHASTIC TRANSPORT IN ION CHANNELS.....	192
<i>I. Kh. Kaufman ; W. A. T. Gibby ; D. G. Luchinsky ; P. V. E. McClintock</i>	
STOCHASTIC MODEL FOR ION SHOT NOISE IN HODGKIN AND HUXLEY NEURONS	196
<i>B. G. Vasallo ; J. Mateos ; T. González</i>	
PERFORMANCE AND SECURITY ANALYSIS OF THE GENERALIZED KIRCHHOFF-LAW-JOHNSON-NOISE KEY EXCHANGE PROTOCOL	200
<i>Robert Mingesz ; Noémi Bors ; Gergely Vadai ; Zoltán Gingl</i>	
NOISE ROBUSTNESS OF COMMUNICATIONS PROVIDED BY COUPLING-FUNCTION-ENCRYPTION AND DYNAMICAL BAYESIAN INFERENCE	204
<i>Tomislav Stankovski ; Peter V. E. McClintock ; Aneta Stefanovska</i>	
NOISE IN GAN HEMTS AND CIRCUITS	208
<i>Matthias Rudolph ; Cristina Andrei ; Ralf Doerner ; Serguei A. Chevtchenko ; Wolfgang Heinrich</i>	
HOT-ELECTRON NOISE SPECTROSCOPY FOR HFET CHANNELS	212
<i>Emilis Šermukšnis ; Juozapas Liberis ; Artur Šimukovic ; Arvydas Matulionis ; Md Barkat Ullah ; Mykyta Toporkov ; Vitaliy Avrutin ; Ümit Özgür ; Hadis Morkoç</i>	
MEMRISTORS AND THERMAL NOISE: IS THE MEMRISTOR INDEED THE MISSING PASSIVE CIRCUIT ELEMENT?	216
<i>K. M. Sundqvist ; L. B. Kish</i>	
LOW FREQUENCY NOISE MEASUREMENTS IN P-TYPE METAL-BASE VERTICAL ORGANIC TRANSISTORS.....	217
<i>G. Giusi ; E. Sarnelli ; M. Barra ; A. Cassinese ; G. Scandurra ; K. Nakayama ; C. Ciofi</i>	
LOW-FREQUENCY NOISE IN TERAHERTZ PLASMONIC FIELD EFFECT TRANSISTORS.....	221
<i>M. S. Shur ; G. Rupper ; S. Rudin</i>	
HIGH FREQUENCY NOISE AND HARMONIC DISTORTION OF 28 NM N AND P TYPE MOSFETS.....	225
<i>P. Sakalas ; K. Yau ; M. Schroter</i>	
EFFECTS OF THE PLASMA PROCESS FOR SELF-ALIGNED NANO-CARBON FIELD-EFFECT TRANSISTORS	229
<i>Toshio Kawahara ; Singh Kumar Rupesh ; Yasuhide Ohno ; Kenzo Maehashi ; Kazuhiko Matsumoto ; Kazumasa Okamoto ; Risa Utsunomiya ; Teruaki Matsuba</i>	
MEASUREMENTS OF FLICKER NOISE IN SUPERCAPACITOR CELLS	233
<i>A. Szweczyk ; L. Lentka ; J. Smulko ; P. Babuchowska ; F. Béguin</i>	
ATOMICALLY FLAT INTERFACE FOR NOISE REDUCTION IN SOI-MOSFETS	237
<i>Philippe Gaubert ; Alexandre Kircher ; Hyeonwoo Park ; Rihito Kuroda ; Shigetoshi Sugawa ; Tetsuya Goto ; Tomoyuki Suwa ; Akinobu Teramoto</i>	
DEEP TRAPS IN $\text{In}_{0.3}\text{Ga}_{0.7}\text{As}$ NFINFETS STUDIED BY GENERATION-RECOMBINATION NOISE.....	241
<i>L. He ; H. Chen ; D. D. Guo ; L. N. Hu ; Y. Qin ; E. Simoen ; C. Claeys ; B. Kunert ; N. Waldron ; N. Collaert</i>	
UNDERSTANDING TRAPS LOCATIONS AND IMPACT ON ALGAN/GAN HEMT BY LFN NOISE & TRANSIENT MEASUREMENTS, AND T-CAD SIMULATIONS	245
<i>J. G. Tartarin ; D. Saugnon ; O. Lazar ; G. Maillot ; L. Bary</i>	

DEMONSTRATION OF LOW-FREQUENCY NOISE MEASUREMENTS FOR STUDYING ELECTROMIGRATION MECHANISMS IN ADVANCED NANO-SCALED INTERCONNECTS	249
<i>Sofie Beyne ; Kristof Croes ; Ingrid De Wolf ; Zsolt Tokei</i>	
ON TRAP IDENTIFICATION IN TRIPLE-GATE FINFETS AND GATE-ALL-AROUND NANOWIRE MOSFETS USING LOW FREQUENCY NOISE SPECTROSCOPY	253
<i>D. Boudier ; B. Cretu ; E. Simoen ; A. Veloso ; N. Collaert</i>	
HOOGE'S PARAMETER IN SI NW FET WITH DIFFERENT WIDTHS	257
<i>I. Zadorozhnyi ; Y. Kutovyi ; H. Hlukhova ; M. Petrychuk ; S. Vitusevich</i>	
IOT FRAMEWORK FOR FLUCTUATION ENHANCED SENSING	261
<i>Robert Mingesz ; Gergely Makan ; Benjamin Balogh ; Gergely Vadai ; Zoltán Gingl</i>	
LOW FREQUENCY NOISE OF ELECTROCHEMICAL POWER SOURCES	265
<i>Tomas Kupařowitz ; Vlasta Sedlakova ; Petr Sedlak ; Josef Sikula</i>	
NOISE LIMITATIONS OF GAN LATERAL SCHOTTKY DIODES FOR THZ APPLICATIONS.....	269
<i>G. Cywinski ; I. Yahniuk ; K. Szkudlarek ; P. Kruszewski ; G. Muziol ; C. Skierbiszewski ; A. Khachapuridze ; W. Knap ; D. But ; S. L. Rumyantsev</i>	
ANALYSIS OF CHARGE STATES IN GAN-BASED NANORIBBONS USING TRANSPORT AND NOISE STUDIES.....	272
<i>I. Zadorozhnyi ; H. Hlukhova ; Y. Kutovyi ; M. Petrychuk ; V. Sydoruk ; V. Handziuk ; S. Vitusevich</i>	
FREQUENCY RESPONSE OF AN ENERGY HARVESTER TO HARMONIC NOISE: TOWARDS STOCHASTIC FREQUENCY RESPONSE OF NONLINEAR SYSTEMS	276
<i>Igor A. Khovanov ; Natasha A. Khovanova</i>	
TRUE RANDOM NUMBERS GENERATION FROM STATIONARY STOCHASTIC PROCESSES.....	280
<i>Giuseppe Martini ; Francesco G. Bruno</i>	
PERFORMANCE ANALYSIS OF SEGMENTATION USING SSR UNDER DIFFERENT NOISE CONDITIONS	284
<i>Sumit Kumar ; Ayush Kumar Rajib Kumar Jha</i>	
EFFECTS OF THICKNESS ON 1/F NOISE OF CO AND IN CO-DOPED ZNO	288
<i>H. Slimi ; A. Achahour ; G. Leroy ; N. Waldhoff ; B. Duponchel ; A. Barhoumi ; S. Guermazi ; M. Dewitte ; K. Blary ; L. K. J. Vandamme</i>	
1/F NOISE AS FUNCTION OF THICKNESS IN AL-DOPED ZNO THIN FILMS	292
<i>A. Achahour ; G. Leroy ; N. Waldhoff ; B. Ayachi ; K. Blary ; J. -P. Vilcot ; L. K. J. Vandamme</i>	
LOW FREQUENCY NOISE IN ADVANCED 55NM BICMOS SIGEC HETEROJUNCTION BIPOLAR TRANSISTORS: IMPACT OF COLLECTOR DOPING	296
<i>B. Sagnes ; F. Pascal ; M. Seif ; A. Hoffmann ; S. Haendler ; P. Chevalier ; D. Gloria</i>	
FIRST PASSAGE THEORY FOR ELECTROCHEMICAL STOCHASTIC DIFFUSION.....	300
<i>B. M. Grafov</i>	
PDF EVOLUTION OF A PULSE TRAIN: A CHARACTERISTIC FUNCTION AND ADAPTIVE SPLINE APPROACH	302
<i>R. M. Howard</i>	
MONTE CARLO SIMULATION OF THZ NOISE AND GENERATION UNDER ELECTRON COOLING IN WURTZITE GAN MOSFET AT ROOM TEMPERATURE	306
<i>V. Gružinskis ; P. Shiktorov ; E. Starikov ; H. Marinchio ; C. Palermo ; J. Torres ; L. Varani</i>	
MICROWAVE NOISE IN EPITAXIAL GRAPHENE ON SIC	309
<i>Linas Ardaravičius ; Juozapas Liberis ; Emilis Šermukšnis ; Joon Young Kwak ; Hussain A. Alsalmān ; Michael G. Spencer</i>	
INVESTIGATION OF (Ge₂Sb₂Te₅)_{1-x}Bi_x THIN FILMS BY LOW FREQUENCY NOISE SPECTROSCOPY.....	313
<i>V. G. Litvinov ; A. V. Ermachikhin ; T. A. Kholomina ; P. I. Lazarenko</i>	
NOISE PARAMETERS OF GAAS PHEMTS AT K, V AND W BANDS: MEASUREMENT PECULIARITIES AND MODELING.....	316
<i>P. Sakalas ; M. Zhang ; M. Schroter ; G. Yujing</i>	
THERMAL NOISE-LIMITED SENSITIVITY OF FET-BASED TERAHERTZ DETECTORS	320
<i>D. Cibiraite ; M. Bauer ; A. Lisauskas ; V. Krozer ; H. G. Roskos ; A. Rāmer ; V. Krozer ; W. Heinrich ; S. Pralgauskaitė ; J. Zdanevicius ; J. Matukas ; A. Lisauskas ; M. Andersson ; J. Stake</i>	
COOLING EFFECTS IN NOISE TEMPERATURE SPECTRUM.....	324
<i>Pavel Shiktorov ; Evgenij Starikov ; Viktoras Gružinskis ; Christophe Palermo ; Jeremie Torres ; Luca Varani</i>	
REDUCING NOISE EQUIVALENT POWER IN INP DHBT TERAHERTZ DETECTOR BY BIASING THE COLLECTOR.....	327
<i>N. Dyakonova ; D. Coquillat ; D. But ; C. Consejo ; F. Teppe ; W. Knap ; L. Varani ; S. Blin ; V. Nodjiadjim ; A. Konczykowska ; M. Riet</i>	
LOW-FREQUENCY NOISE VERSUS DEEP LEVEL TRANSIENT SPECTROSCOPY OF INAS/GASB SUPERLATTICE MID-WAVELENGTH INFRARED DETECTORS	331
<i>Ll. Ciura ; A. Kolek ; J. Wróbel ; P. Martyniuk</i>	

MID-INFRARED LASER DIODES INVESTIGATION VIA LOW-FREQUENCY NOISE SPECTROSCOPY AND ELECTRICAL DERIVATIVE CHARACTERISTICS.....	335
<i>Justinas Glemža ; Jonas Matukas ; Sandra Pralgauskaite ; Vilius Palenskis</i>	
LOW-FREQUENCY NOISE IN QUASI-1D TASE3 VAN DER WAALS NANOWIRES	339
<i>G. Liu ; A. A. Balandin ; S. L. Rumyantsev ; M. S. Shur ; M. A. Bloodgood ; T. T. Salguero</i>	
INVESTIGATION OF BAND DIAGRAM FEATURES OF THE DUWELL-STRUCTURE INAS/INGAAS/GAAS BY DLTS AND LOW-FREQUENCY NOISE SPECTROSCOPY	343
<i>V. G. Litvinov ; A. V. Ermachikhin ; D. S. Kusakin</i>	
FAST ALGORITHM OF LONG-RANGE CROSS-CORRELATION ANALYSIS USING SAVITZKY-GOLAY DETRENDING FILTER AND ITS APPLICATION TO BIOSIGNAL ANALYSIS	346
<i>Yutaka Tsujimoto ; Yuki Miki ; Eiichi Watanabe ; Junichiro Hayano ; Yoshiharu Yamamoto ; Taishin Nomura ; Ken Kiyono</i>	
DETRENDED FLUCTUATION ANALYSIS OF REPETITIVE HANDWRITING	350
<i>Ryo Kumagai ; Masafumi Uchida</i>	
SHORT NOISE SUPPRESSION FACTOR FOR NANO-SCALE MOSFETS WORKING IN THE SATURATION REGION.....	354
<i>Xuesong Chen ; Chih-Hung Chen ; M. Jamal Deen</i>	
STATISTICAL ANALYSIS OF 1/F NOISE IN ENCLOSED-GATE N- AND PMOS TRANSISTORS.....	358
<i>Aristeidis Nikolaou ; Nikolaos Mavredakis ; Matthias Bucher ; Predrag Habas ; Alexandre Acovic ; René Meyer</i>	
CARRIER DENSITY AND MOBILITY FLUCTUATIONS DUE TO CARRIER RETRAPPING PROCESS IN HOMOGENEOUS SEMICONDUCTORS.....	362
<i>Vilius Palenskis ; Justinas Glemža ; Juozas Vyšniauskas ; Jonas Matukas</i>	
INVESTIGATION AND SIMULATION OF VOLTAGE-NOISE CHARACTERISTICS OF SEMICONDUCTOR BARRIER STRUCTURES	366
<i>T. A. Kholomina ; V. G. Litvinov ; A. R. Semenov ; A. V. Ermachikhin ; A. D. Maslov</i>	
MEASUREMENT COMPLEX TO INVESTIGATE ELECTROPHYSICAL AND NOISE CHARACTERISTICS OF SEMICONDUCTOR MICRO- AND NANOSTRUCTURES	370
<i>V. G. Litvinov ; A. V. Ermachikhin ; D. S. Kusakin ; N. V. Vishnyakov ; A. D. Maslov ; A. R. Semenov</i>	
UNIFIED NOISE CHARACTERIZATION TECHNIQUE FOR MOSFETS	374
<i>Suba Subramaniam ; Alexander Petr ; Michaelina Ong Ing Ing</i>	
LOW FREQUENCY NOISE MEASUREMENTS AS AN EARLY INDICATOR OF DEGRADATION FOR DEVICES ON PLASTIC SUBSTRATES SUBJECTED TO MECHANICAL STRESS	379
<i>G. Scandurra ; A. Arena ; G. Giusi ; G. Cannatà ; C. Ciofi</i>	
LOW-FREQUENCY NOISE IN SI NW FET FOR ELECTRICAL BIOSENSING	383
<i>Y. Kutovy ; I. Zadorozhnyi ; H. Hlukhova ; M. Petrychuk ; S. Vitusevich</i>	
NOISE FLUCTUATION CHANGES RELATED TO EDGE DELETION OF THIN-FILM CU(IN,GA)SE2 SOLAR CELLS.....	387
<i>L. Skvarenina ; R. Macku ; P. Skarvada ; A. Gajdos ; J. Sikula</i>	
NOISE-INDUCED TRAVELING WAVES IN ELECTROCONVECTION.....	391
<i>Jong-Hoon Huh</i>	
CHARACTERIZATION OF SUPRA-THRESHOLD STOCHASTIC RESONANCE FOR UNIFORM DISTRIBUTED SIGNAL WITH LAPLACIAN AND GAUSSIAN NOISE.....	395
<i>Sumit Kumar ; Rajib Kumar Jha ; Aakanksha</i>	
PATTERN FORMATIONS IN ELECTROCONVECTION BY COLORED NOISE	399
<i>Yoshimitsu Yano ; Jong-Hoon Huh</i>	
Author Index	